Search Notes

Applicat	ion/Con	trol	No.	

Applicant(s)/Patent under Reexamination

10/657,054 Examiner PLESKACH ET AL.
Art Unit

Paul D. Kim

3729

SEARCHED			
Class	Subclass	Date	Examiner
29	602.1 604-606	6/15/2005	PK
336	176 200 229	6/15/2005	PK
156	89.11 89.12	6/15/2005	PK
	250		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	17		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text Search EAST/NPL (IEEE)	6/16/2005	PK
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